

Application/Control No.	Applicant(s)/Patent Reexamination	under
10/525,862	VAN DE BEEK ET AL.	
Examiner	Art Unit	
Ryan C Jager	2816	

	SEARCHED				
Class	Subclass	Date	Examiner		
327	147	5-15-06	br2 br2		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
PG-Pi	B	1/8/07	Res.	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
(INCLODING SEARCH	DATE	EXMR
Imuted text search (see notes)	51C-0G	RES
tent search (see notes)	5-16-06	RCS
test scorch (see notes)	4-17-06	pc5
(see votes) update above	5-17-06	RLJ.
updake above	1435/06	PCJ
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